



## IO-Link EMC Test System for Devices

### Overview

The IO-Link specification defines the environmental tests (EMC) for the SDCI communication part of an IO-Link device.

The tests require a master that is much less sensitive to EMC noise than the device under test. This is achieved by separating the IO-Link master into two parts: part 1 contains the sensitive digital logic ( $\mu$ C-box); part 2 contains the IO-Link transceiver (PHY-box).

Both parts are separated by an optical connection with a length of up to 10m.

### Advantages

- Sensitive parts are located outside the EMC chamber
- EMC robustness considerably better than required

### Deliverables

- 2 EMC test boxes (Controller-box and PHY-box)
- 6 Optical cables
- 2 connectors for 24V supply
- EMC Tester Application (for Windows)
- IO-Link Control Tool (for Windows)



IO-Link EMC Test System. Universal, smart, easy.

### Features

- Complies with the IO-Link Interface Specification V1.1.2 and the current IO-Link Test Specification
- Error and Signal output
- 4 electrical IO-Link port configurations
  - COM1/2 speed port (good signal)
  - COM1/2 speed port (bad signal)
  - COM3 speed port (good signal)
  - COM3 speed port (bad signal)
- RS232 and USB interfaces
- Terminal based control command set
- Additional EMC test and control software with graphical user interface
- Test report generation in PDF Format
- Can be configured to operate as standard "USB IO-Link Master"
- Firmware update supported

